

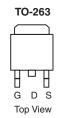
# N-Channel 100-V (D-S) MOSFET

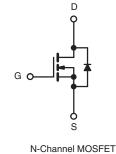
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)			
100	0.010 at V <sub>GS</sub> = 10 V	100			
	0.023 at V <sub>GS</sub> = 4.5 V	85			

#### FEATURES

- TrenchFET<sup>®</sup> Power MOSFET
- 175 °C Maximum Junction Temperature
- Compliant to RoHS Directive 2002/95/EC







<b>ABSOLUTE MAXIMUM RATINGS</b> $T_A = 25 \degree C$ , unless otherwise noted						
Parameter			Limit	Unit		
Drain-Source Voltage			100	V		
Gate-Source Voltage			± 20	v		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 25 °C	I <sub>D</sub>	100			
	T <sub>C</sub> = 125 °C		75 <sup>a</sup>	•		
Pulsed Drain Current	I <sub>DM</sub>	300	A			
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	75			
Single Pulse Avalanche Energy <sup>b</sup>	L = 0.1 mm	E <sub>AS</sub>	280	mJ		
Maximum Power Dissipation <sup>b</sup>	$T_{C} = 25 \ ^{\circ}C \ (TO-220AB \text{ and } TO-263)$	PD	250 <sup>c</sup>	w		
	T <sub>A</sub> = 25 °C (TO-263) <sup>d</sup>	۰D	3.75			
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Limit	Unit		
Junction-to-Ambient	PCB Mount (TO-263) <sup>d</sup>	- R <sub>thJA</sub>	40			
Junction-to-Ambient	Free Air (TO-220AB)		62.5	°C/W		
Junction-to-Case		R <sub>thJC</sub>	0.6			

Notes:

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## IRF8010SP

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	·	·					
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA 100					
Gate-Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	2		4	V	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
		$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		1			
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 ^{\circ}\text{C}$			50	μA	
		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 175 ^{\circ}\text{C}$			250		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} = \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		0.010		1	
	В	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 20 A		0.023		Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 30 \text{ A}, \text{ T}_{J} = 125 ^{\circ}\text{C}$		0.020			
		$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 30 \text{ A}, \text{ T}_{J} = 175 ^{\circ}\text{C}$		0.030			
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A	25			S	
Dynamic <sup>b</sup>		•	•	•			
Input Capacitance	C <sub>iss</sub>			6550			
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1 MHz		665		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			265			
Total Gate Charge <sup>c</sup>	Qg			105	160		
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 85 \text{ A}$		17		nC	
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>			23			
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			12	25		
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD}$ = 50 V, $R_L$ = 0.6 $\Omega$		90	135	- ns	
Turn-Off DelayTime <sup>c</sup>	t <sub>d(off)</sub>	$I_D \cong 85 \text{ A}, V_{GEN} = 10 \text{ V}, \text{ R}_g = 2.5 \Omega$		55	85		
Fall Time <sup>c</sup>	t <sub>f</sub>			130	195		
Source-Drain Diode Ratings and Char	racteristics T <sub>C</sub> :	= 25 °C <sup>b</sup>					
Continuous Current	ا <sub>S</sub>				85	٨	
Pulsed Current	I <sub>SM</sub>				240	A	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = 85 A, V <sub>GS</sub> = 0 V		1.0	1.5	V	
Reverse Recovery Time	t <sub>rr</sub>			85	140	ns	
Peak Reverse Recovery Current	I <sub>RM(REC)</sub>	I <sub>F</sub> = 50 A, dl/dt = 100 A/μs		4.5	7	Α	
Reverse Recovery Charge	Q <sub>rr</sub>	1		0.17	0.35	μC	

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Notes:

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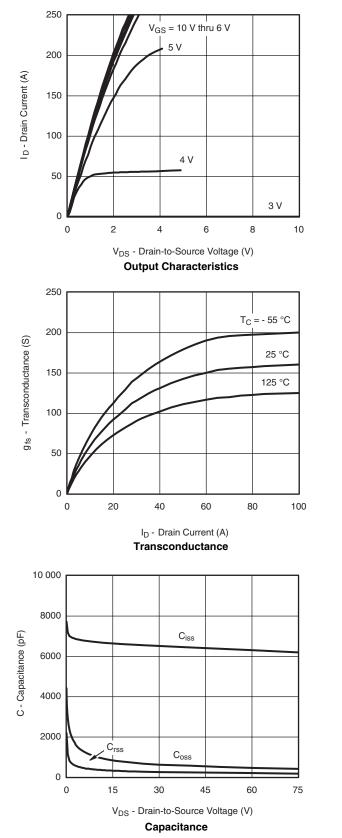
b. Guaranteed by design, not subject to production testing.

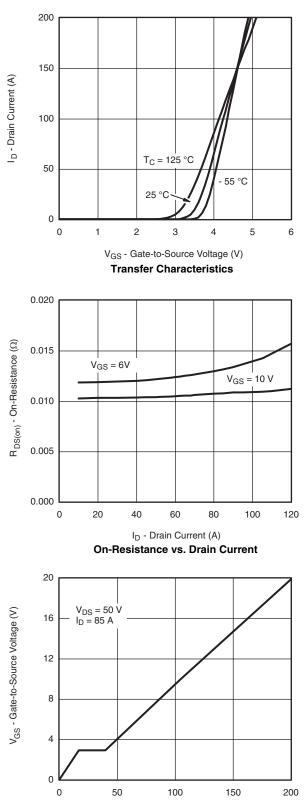
c. Independent of operating temperature.

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#### **TYPICAL CHARACTERISTICS** $T_A = 25 \text{ °C}$ , unless otherwise noted



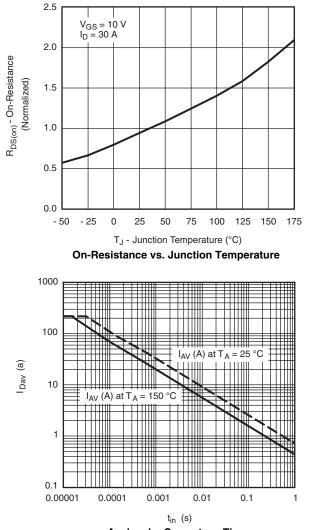


Q<sub>q</sub> - Total Gate Charge (nC)

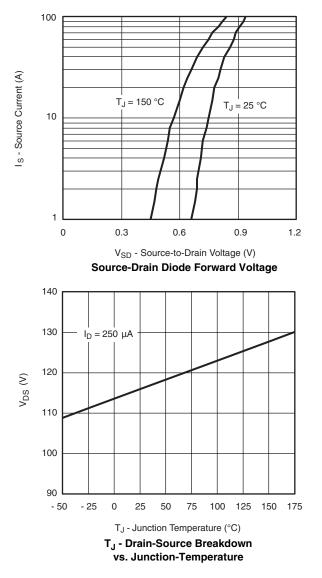
Gate Charge



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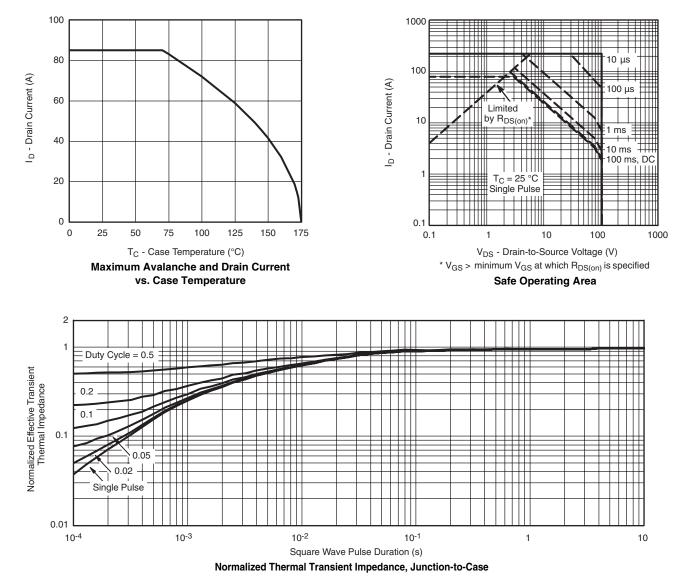
Avalanche Current vs. Time



## IRF8010SP

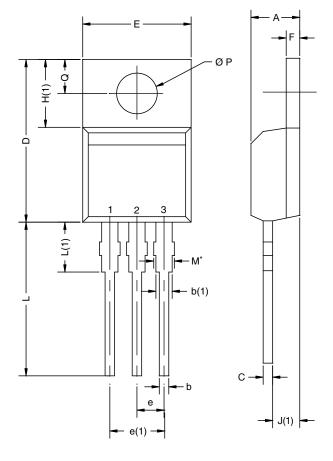


#### **THERMAL RATINGS**





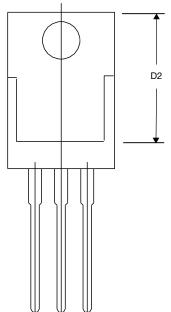
## **TO-220AB**



	MILLIN	IETERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
с	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
D2	12.19	12.70	0.480	0.500	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471					

#### Note

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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